

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE JAN 14 2005 LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		ATTY DOCKET NO. <b>03500.017504</b>	APPLICATION NO. <b>10/647,287</b>
APPLICANTS <b>MITSUTOSHI HASEGAWA ET AL.</b>			
FILING DATE <b>August 26, 2003</b>			GROUP <b>n/y/a</b>

  

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
KR	6,060,113	05/00	Banno et al.	427	125		
	6,296,896 B1	10/01	Takahashi et al.	427	77		
	2003/0067263 A1	04/03	Tokioka et al.	313	493	08/28/02	
	6,624,586 B2	09/03	Abe et al.	315	169.1		
	5,455,597	10/95	Nakamura et al.	345	75		
	5,659,329	08/97	Yamanobe et al.	345	74		
KR	6,137,218	10/00	Kaneko et al.	313	495		

  

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
	JP 7-326311	12/95	Japan			Abstract	
	JP 8-185818	07/96	Japan			Abstract	
	JP 9-50757	02/97	Japan			Abstract	
	JP 9-102271	04/97	Japan			Abstract	
	JP 2000-251665	9/00	Japan			Abstract	

  

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
	M. Hartwell et al, "Strong electron emission from patterned tin-indium oxide thin films", International Electron Devices Meeting 1975, Washington, D.C., Catalog No. 75, CH1023-1, IEDM Technical Digest, pp. 519-521.

  

EXAMINER <i>[Signature]</i>	DATE CONSIDERED <b>4/5/05</b>
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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APPLICANT <b>mitsutoshi HASEGAWA ET AL.</b>							
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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
KR		6,254,449 B1	07/01	Nakanishi et al.	445	25	08/98
		6,283,813 B1	09/01	Kaneko et al.	445	24	
		2002/0180342 A1	12/02	Yamada et al.	313	493	07/02
		6,506,089 B2	01/03	Nakanishi et al.	445	25	02/01
KR		2003/0058192 A1	03/03	Arai et al.	345	59	09/02

  

FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	JP	64-31332	2/89	Japan			Abstract
	JP	6-342636	12/94	Japan			Abstract
	JP	11-135018	05/99	Japan			Abstract
	JPP	2001-210258	8/01	Japan			Abstract

  

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		

  

EXAMINER <i>K. Rose</i>	DATE CONSIDERED <b>4/5/05</b>
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